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(54) Title: **DEVICE, ASSEMBLY AND METHOD FOR TESTING ELECTRONIC COMPONENTS, AND CALIBRATING METHOD THEREFOR**

(57) Abstract

The invention relates to a test device for testing electronic components mounted on a carrier such as a lead frame, comprising: a transport path for supplying a carrier for testing, a manipulator for engaging and displacing a supplied carrier, a test contact with which a carrier and/or at least one component mounted on the carrier can be placed in contact by the manipulator, and a transport path for discharging a tested carrier. The invention also embraces a test assembly which includes at least one described test device. The invention furthermore provides a method for testing electronic components mounted on a carrier and method for calibrating a test device.

